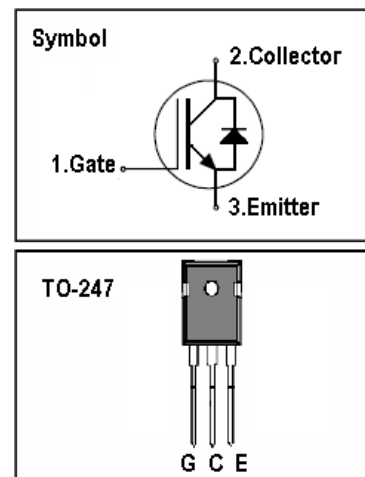


600V, 25A, Trench NPT IGBT

Features

- 600V, 25A
- $V_{CE(sat)}(typ.)=1.9V@V_{GE}=15V, I_C=25A$
- High speed switching
- Higher system efficiency
- Soft current turn-off waveforms
- Square RBSOA using NPT technology



Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{CES}	Collector-Emitter Voltage	600	V
V_{GES}	Gate-Emitter Voltage	± 30	V
I_C	Continuous Collector Current ($T_C=25^\circ C$)	45	A
	Continuous Collector Current ($T_C=100^\circ C$)	25	A
I_{CM}	Pulsed Collector Current (Note 1)	80	A
I_F	Diode Continuous Forward Current ($T_C=100^\circ C$)	20	A
I_{FM}	Diode Maximum Forward Current (Note 1)	40	A
t_{sc}	Short Circuit Withstand Time	10	us
P_D	Maximum Power Dissipation ($T_C=25^\circ C$)	200	W
	Maximum Power Dissipation ($T_C=100^\circ C$)	100	W
T_J	Operating Junction Temperature Range	-55 to +150	$^\circ C$
T_{STG}	Storage Temperature Range	-55 to +150	$^\circ C$

Thermal Characteristics

Symbol	Parameter	Max.	Units
$R_{th j-c}$	Thermal Resistance, Junction to case for IGBT	0.63	$^\circ C/W$
$R_{th j-c}$	Thermal Resistance, Junction to case for Diode	1.5	$^\circ C/W$
$R_{th j-a}$	Thermal Resistance, Junction to Ambient	40	$^\circ C/W$

Electrical Characteristics (T_C=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV _{CES}	Collector-Emitter Breakdown Voltage	V _{GE} = 0V, I _C = 250uA	600	-	-	V
I _{CES}	Collector-Emitter Leakage Current	V _{CE} = 1200V, V _{GE} = 0V	-	-	250	uA
I _{GES}	Gate Leakage Current, Forward	V _{GE} =30V, V _{CE} = 0V	-	-	100	nA
	Gate Leakage Current, Reverse	V _{GE} = -30V, V _{CE} = 0V	-	-	-100	nA
V _{GE(th)}	Gate Threshold Voltage	V _{GE} = V _{CE} , I _C = 250uA	3.5	-	5.5	V
V _{CE(sat)}	Collector-Emitter Saturation Voltage	V _{GE} =15V, I _C = 25A	-	1.9		V
Q _g	Total Gate Charge	V _{CC} =480V V _{GE} =15V I _C =25A	-	90		nC
Q _{ge}	Gate-Emitter Charge		-	36		nC
Q _{gc}	Gate-Collector Charge		-	26		nC
t _{d(on)}	Turn-on Delay Time	V _{CC} =300V V _{GE} =15V I _C =25A R _G =28Ω Inductive Load T _C =25 °C	-	47	-	ns
t _r	Turn-on Rise Time		-	51	-	ns
t _{d(off)}	Turn-off Delay Time		-	97	-	ns
t _f	Turn-off Fall Time		-	260	-	ns
E _{on}	Turn-on Switching Loss		-	0.47	-	mJ
E _{off}	Turn-off Switching Loss		-	0.41	-	mJ
E _{ts}	Total Switching Loss		-	0.88	-	mJ
C _{ies}	Input Capacitance	V _{CE} =25V V _{GE} =0V f = 100kHz	-	1250	-	pF
C _{oes}	Output Capacitance		-	150	-	pF
C _{res}	Reverse Transfer Capacitance		-	45	-	pF
R _{Gint}	Integrated gate resistor			39		Ω

Electrical Characteristics of Diode (T_C=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V _F	Diode Forward Voltage	I _F =20A	-	1.5	2.0	V
t _{rr}	Diode Reverse Recovery Time	V _{CE} = 300V	-	65		ns
I _{rr}	Diode peak Reverse Recovery Current	I _F = 20A	-	6		A
Q _{rr}	Diode Reverse Recovery Charge	dI _F /dt = 200A/us	-	200		nC

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature

Typical Performance Characteristics

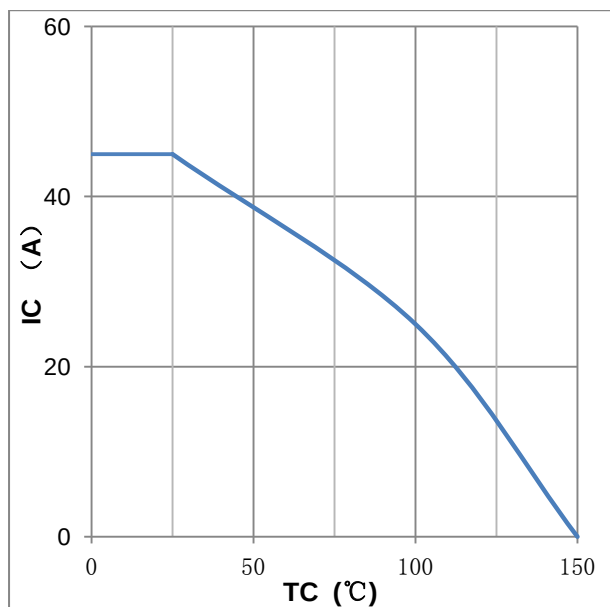


Figure1:maximum DC collector current
VS. case temprature

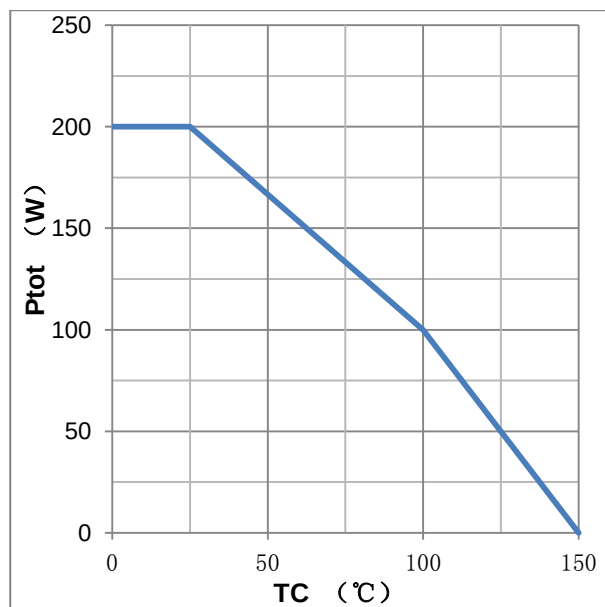


Figure2:power dissipation VS. case temprature

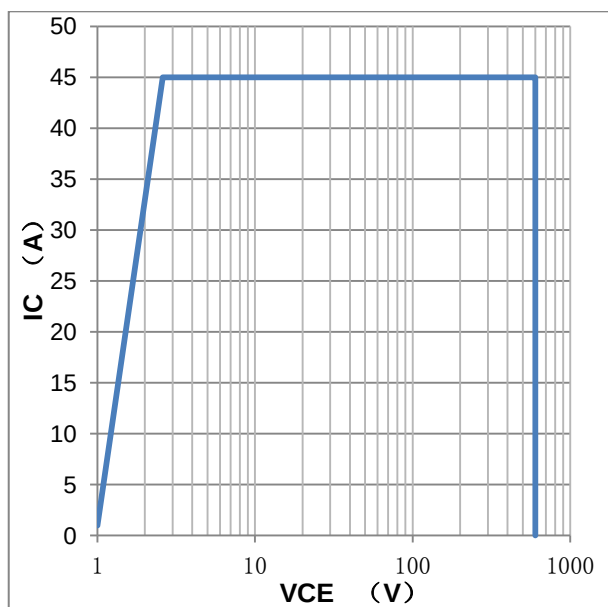


Figure3:reverse bias SOA, $T_J=150^{\circ}\text{C}$, $V_{GE}=15\text{V}$

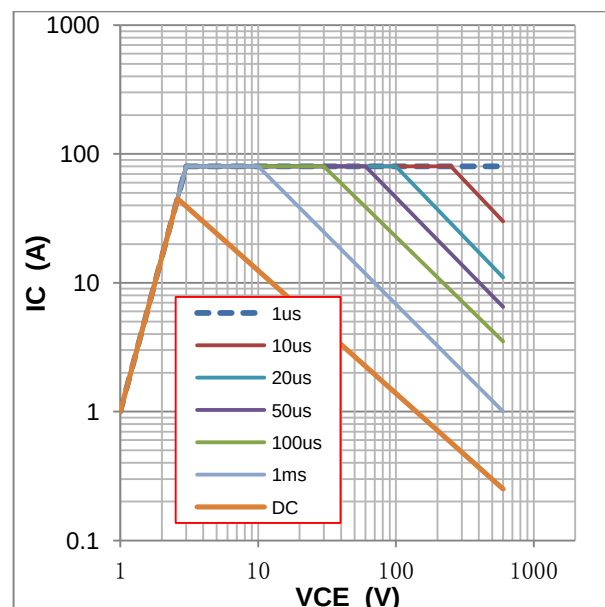


Figure4:forward SOA, $T_C=25^{\circ}\text{C}$, $T_J \leq 150^{\circ}\text{C}$

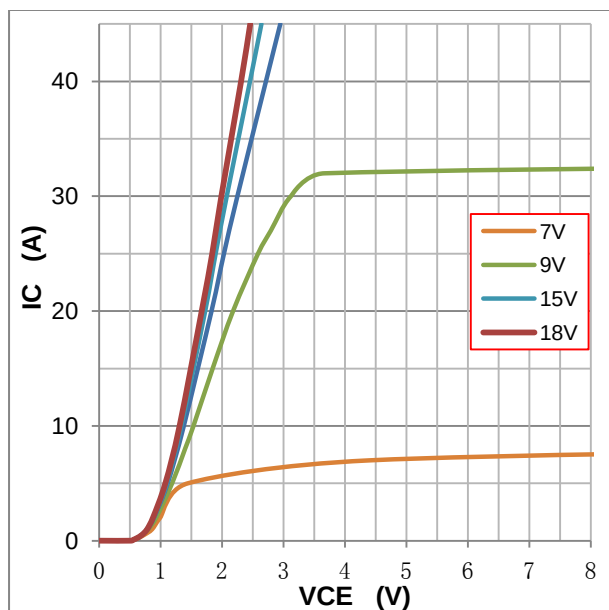


Figure5:typical IGBT output characteristics,
 $T_J=25^{\circ}\text{C}$; $t_p=300\mu\text{s}$

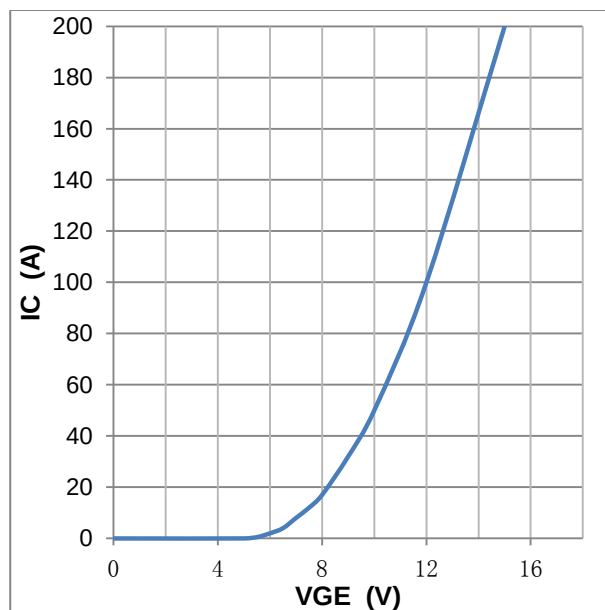


Figure6:typical trans characteristics, $V_{CE}=20\text{V}$, $t_p=20\mu\text{s}$

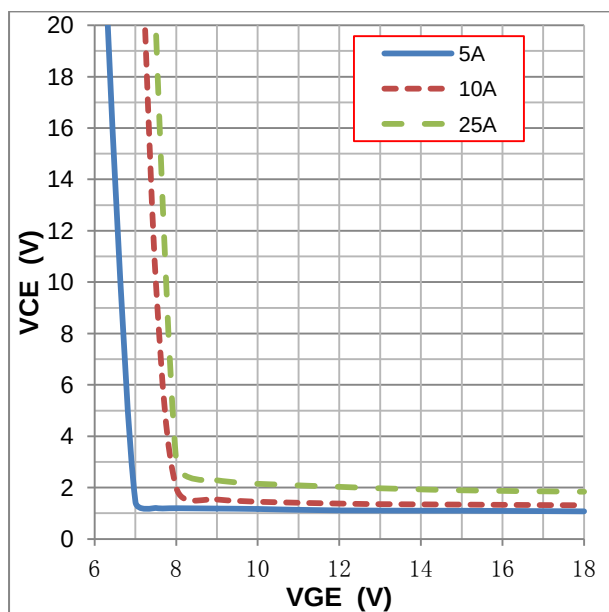


Figure7: typical V_{CE} VS. V_{GE} , $T_J=25^{\circ}\text{C}$

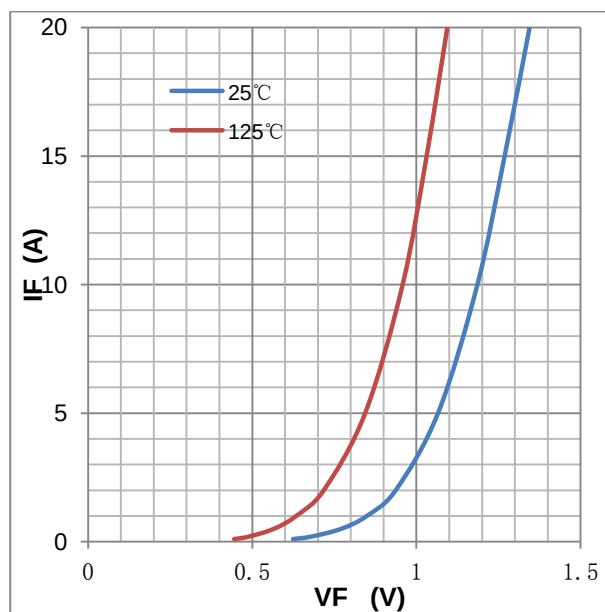


Figure8:typical diode forward characteristic, $t_p=300\mu\text{s}$

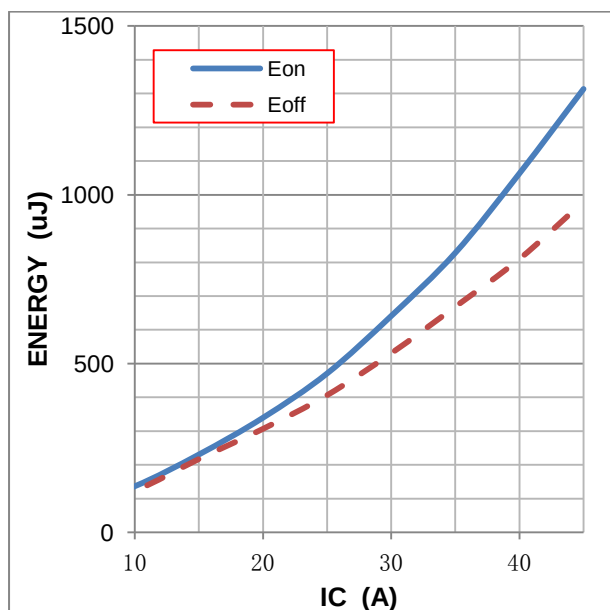


Figure9: typical energy loss VS. IC, TC=25°C,
L=500uH, VCE=300V, VGE=15V, Rg=28Ω,

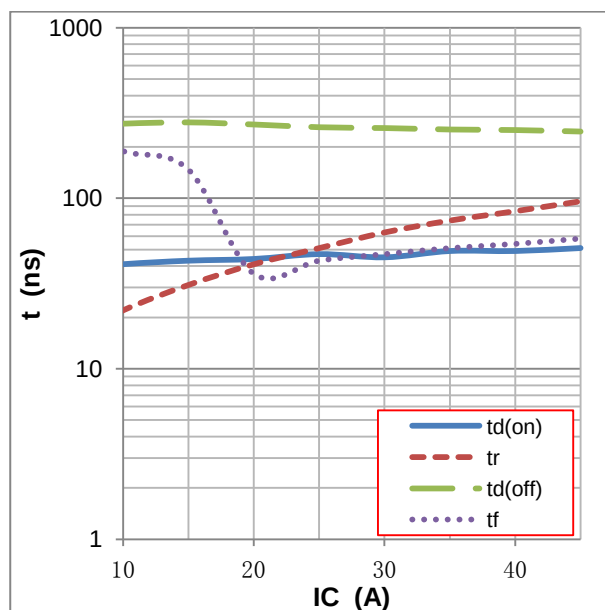


Figure10: typical switching time VS. IC, TC=25°C,
L=500uH, VCE=300V, VGE=15V, Rg=28Ω,

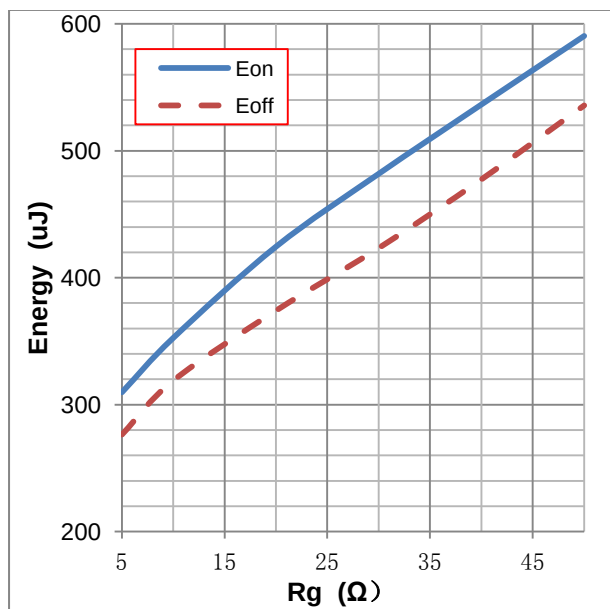


Figure11: typical energy loss VS. Rg, TC=25°C,
L=500uH, VCE=300V, VGE=15V, IC=25A

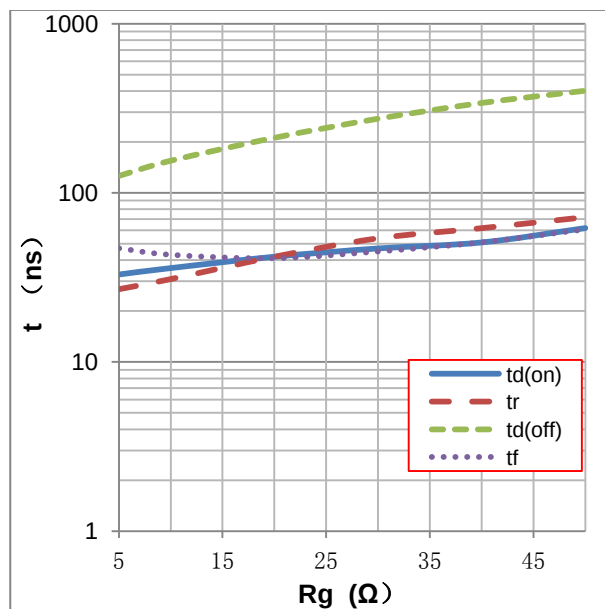


Figure12: typical switching time VS. Rg, TC=25°C,
L=500uH, VCE=300V, VGE=15V, IC=25A

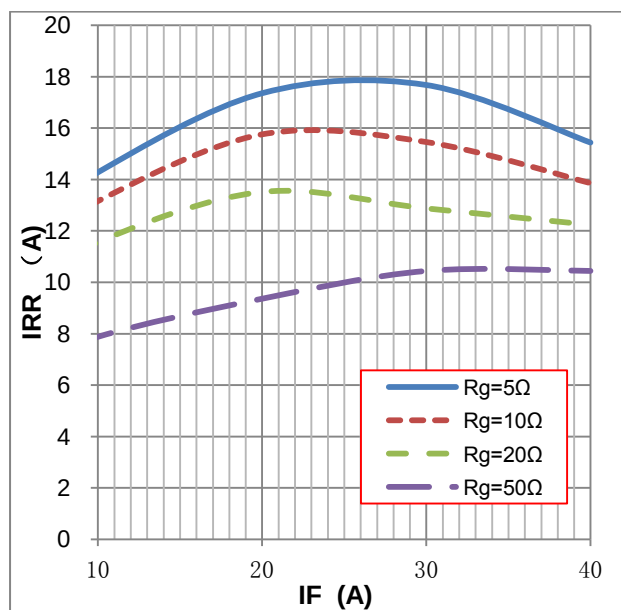


Figure13: typical diode IRR VS. IF, TC=25°C

VCC=300V, VGE=15V

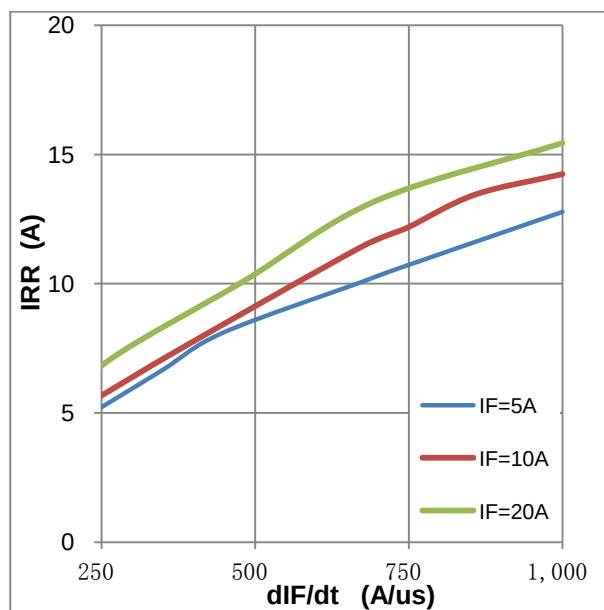


Figure14: typical diode IRR VS. dIF/dt

VCC=300V, VGE=15V

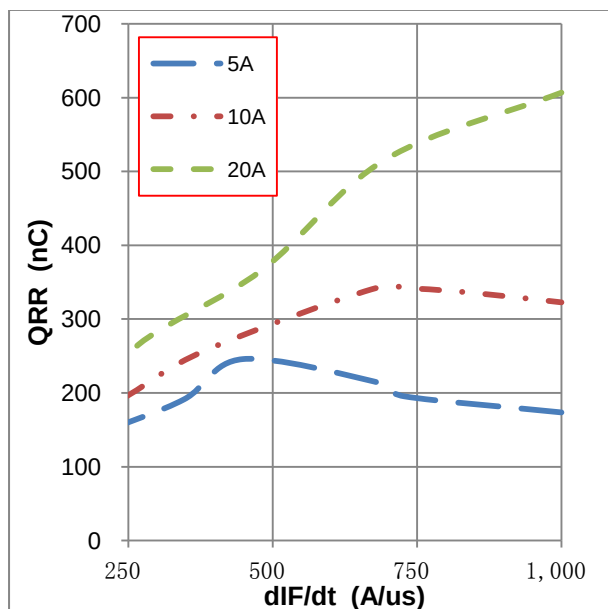


Figure15: typical diode QRR VS. dIF/dt

VCC=300V, VGE=15V

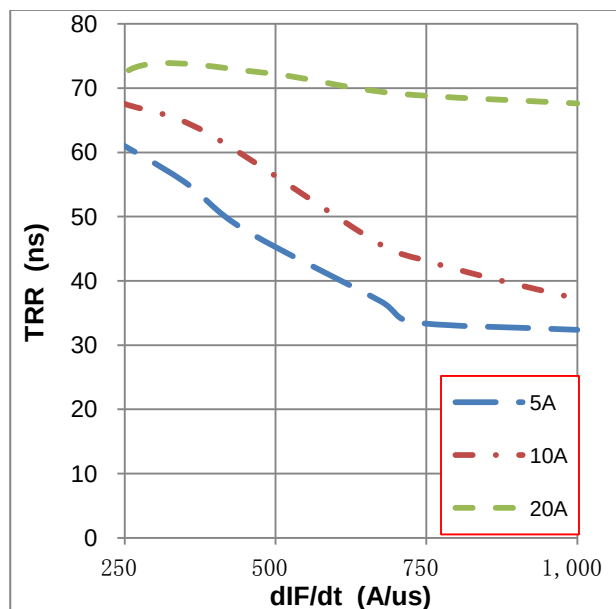


Figure16: typical diode TRR VS. dIF/dt,

VCC=300V, VGE=15V

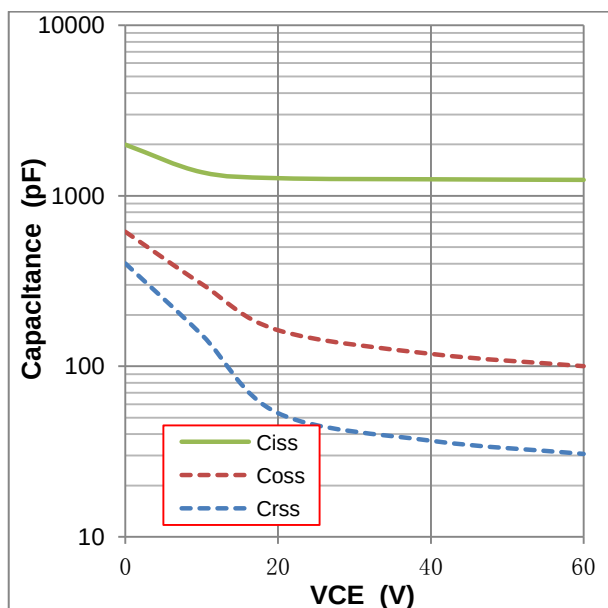


Figure17:typical capacitance VS. VCE,VGE=0V,f=100kHz

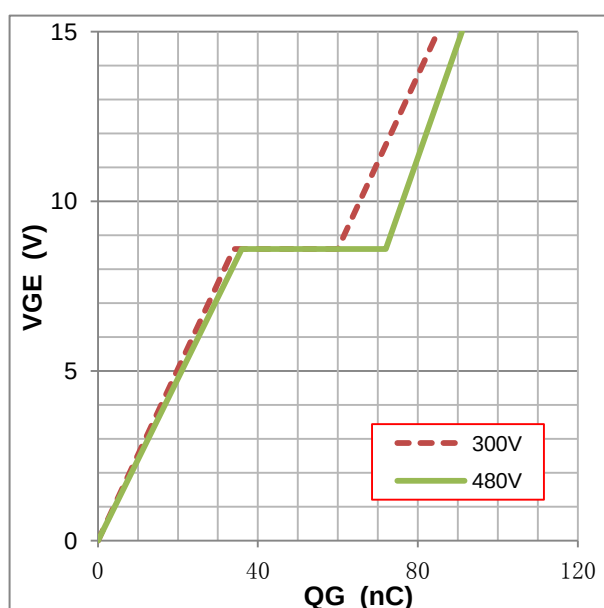


Figure18:typical gate charge VS. VGE,IC=25A

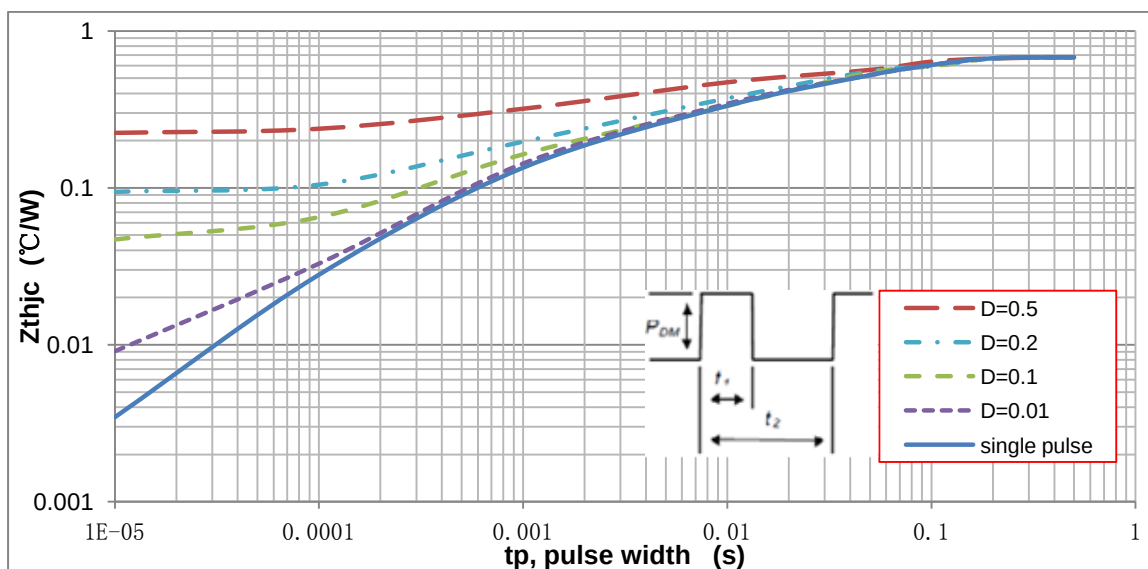
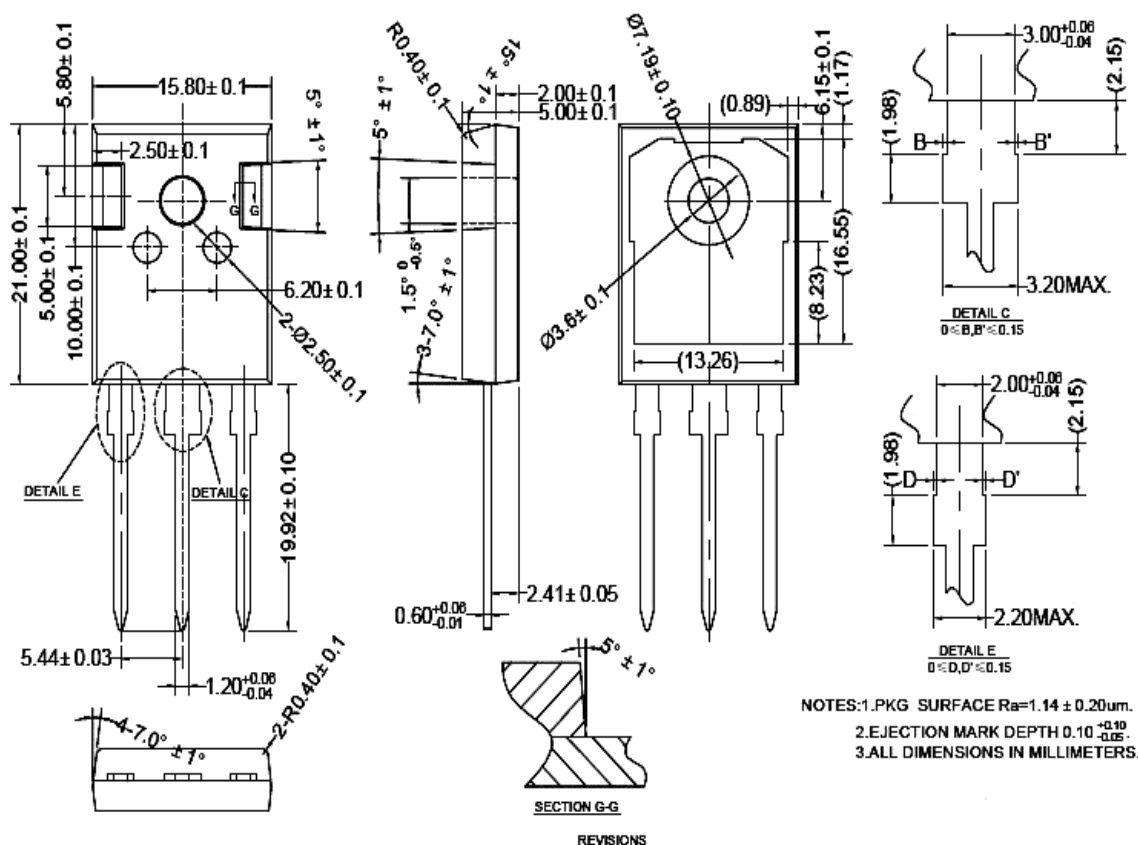


Figure19:normalized transient thermal impedance, junction-to-case

Note1.Duty factor $D=t_1/t_2$;

Note2:peak $T_J=P_{DM} \times Z_{thjc}+T_C$

TO247 PACKAGE OUTLINE



公差标注	公差值	表面粗糙度
0	±0.2	Ra3.2~6.3
0.0	±0.1	Ra1.6~3.2
0.00	±0.01	Ra0.8~1.6
0.000	±0.005	Ra0.4~0.8
0.0000	±0.002	Ra0.2~0.4

0 ≤ D, D' ≤ 0.15

NOTES: 1. PKG SURFACE Ra=1.14 ± 0.20µm.
2. EJECTION MARK DEPTH 0.10 ^{+0.10}/_{-0.05}.
3. ALL DIMENSIONS IN MILLIMETERS.